PowerMOS transistor
Isolated version of BUK455-200A/B

BUK475-200A/B

GENERAL DESCRIPTION

N-channel enhancement mode field-effect power transistor in a plastic full-pack envelope. The device is intended for use in Switched Mode Power Supplies (SMPS), motor control, welding, DC/DC and AC/DC converters, and in general purpose switching applications.

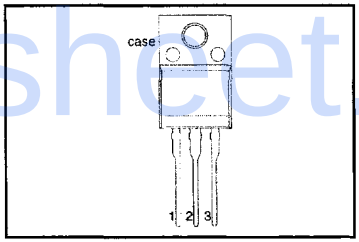
QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	MAX.	UNIT
		BUK475	-200A	-200B	
V_{DS}	Drain-source voltage	200	200	V
I_D	Drain current (DC)	7.6	7	A
P_{tot}	Total power dissipation	30	30	W
T_j	Junction temperature	150	150	°C
$R_{DS(ON)}$	Drain-source on-state resistance	0.23	0.28	Ω

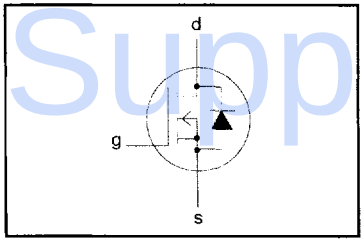
PINNING - SOT186A

PIN	DESCRIPTION
1	gate
2	drain
3	source
case	isolated

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.		UNIT
V_{DS}	Drain-source voltage	-	-	200		V
V_{DGR}	Drain-gate voltage	R_{GS} = 20 kΩ	-	200		V
$\pm V_{GS}$	Gate-source voltage	-	-	30		V
				-200A	-200B	
I_D	Drain current (DC)	T_{hs} = 25 °C	-	7.6	7	A
I_D	Drain current (DC)	T_{hs} = 100 °C	-	4.8	4.4	A
I_{DM}	Drain current (pulse peak value)	T_{hs} = 25 °C	-	30	28	A
P_{tot}	Total power dissipation	T_{hs} = 25 °C	-	30		W
T_{stg}	Storage temperature	-	-55	150		°C
T_j	Junction temperature	-	-	150		°C

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{th\ j\text{-}hs}$	Thermal resistance junction to heatsink	with heatsink compound	-	-	4.17	K/W
$R_{th\ j\text{-}a}$	Thermal resistance junction to ambient		-	55	-	K/W

STATIC CHARACTERISTICS

T_{hs} = 25 °C unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)DSS}$	Drain-source breakdown voltage	V_{GS} = 0 V; I_D = 0.25 mA	200	-	-	V
$V_{GS(TO)}$	Gate threshold voltage	V_{DS} = V_{GS}; I_D = 1 mA	2.1	3.0	4.0	V
I_{DSS}	Zero gate voltage drain current	V_{DS} = 200 V; V_{GS} = 0 V; T_j = 25 °C	-	1	10	µA
I_{DSS}	Zero gate voltage drain current	V_{DS} = 200 V; V_{GS} = 0 V; T_j =125 °C	-	0.1	1.0	mA
I_{GSS}	Gate source leakage current	V_{GS} = ±30 V; V_{DS} = 0 V	-	10	100	nA
$R_{DS(ON)}$	Drain-source on-state resistance	V_{GS} = 10 V; **BUK475-200A**	-	0.2	0.23	Ω
		I_D = 7 A **BUK475-200B**	-	0.22	0.28	Ω

DYNAMIC CHARACTERISTICS

T_{hs} = 25 °C unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
g_{fs}	Forward transconductance	V_{DS} = 25 V; I_D = 7 A	6	8.4	-	S
C_{iss}	Input capacitance	V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz	-	1400	1750	pF
C_{oss}	Output capacitance		-	190	250	pF
C_{rss}	Feedback capacitance		-	55	80	pF
$t_{d\,on}$	Turn-on delay time	V_{DD} = 30 V; I_D = 3 A;	-	18	30	ns
t_r	Turn-on rise time	V_{GS} = 10 V; R_{GS} = 50 Ω;	-	35	60	ns
$t_{d\,off}$	Turn-off delay time	R_{gen} = 50 Ω	-	85	120	ns
t_f	Turn-off fall time		-	35	50	ns
L_d	Internal drain inductance	Measured from drain lead 6 mm from package to centre of die	-	4.5	-	nH
L_s	Internal source inductance	Measured from source lead 6 mm from package to source bond pad	-	7.5	-	nH

ISOLATION LIMITING VALUE & CHARACTERISTIC

T_{hs} = 25 °C unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V_{isol}	R.M.S. isolation voltage from all three terminals to external heatsink	f = 50-60 Hz; sinusoidal waveform; R.H. ≤ 65% ; clean and dustfree	-		2500	V
C_{isol}	Capacitance from T2 to external heatsink	f = 1 MHz	-	10	-	pF

REVERSE DIODE LIMITING VALUES AND CHARACTERISTICS

T_{hs} = 25 °C unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_{DR}	Continuous reverse drain current	-	-	-	7.6	A
I_{DRM}	Pulsed reverse drain current	-	-	-	30	A
V_{SD}	Diode forward voltage	I_F = 7.6 A ; V_{GS} = 0 V	-	1.0	1.5	V
t_{rr}	Reverse recovery time	I_F = 7.6 A; -dI_F/dt = 100 A/µs;	-	150	-	ns
Q_{rr}	Reverse recovery charge	V_{GS} = 0 V; V_R = 30 V	-	1.3	-	µC

AVALANCHE LIMITING VALUE

T_{hs} = 25 ˚C unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
W_{DSS}	Drain-source non-repetitive unclamped inductive turn-off energy	I_D = 14 A ; $V_{DD} \leq$ 100 V ; V_{GS} = 10 V ; R_{GS} = 50 Ω	-	-	100	mJ

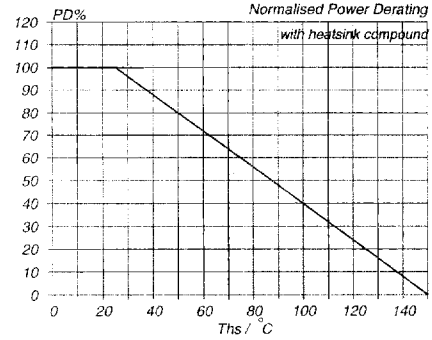


Fig.1. Normalised power dissipation.
PD% = 100·P_D/$P_{D\,25\,˚C}$ = f(T_{hs})

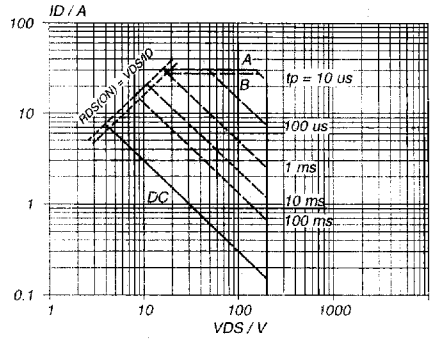


Fig.3. Safe operating area. T_{hs} = 25 ˚C
I_D & I_{DM} = f(V_{DS}); I_{DM} single pulse; parameter t_p

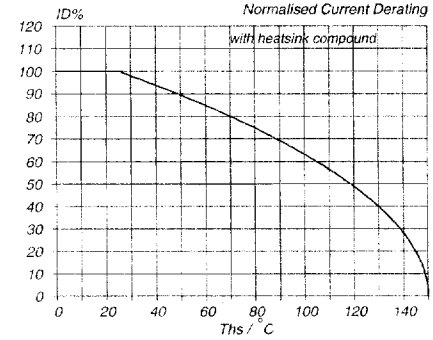


Fig.2. Normalised continuous drain current.
ID% = 100·I_D/$I_{D\,25\,˚C}$ = f(T_{hs}); conditions: $V_{GS} \geq$ 10 V

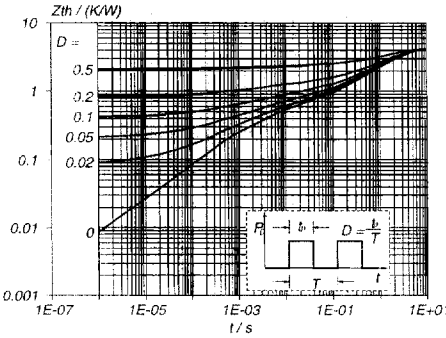


Fig.4. Transient thermal impedance.
$Z_{th\,j\text{-}hs}$ = f(t); parameter D = t_p/T

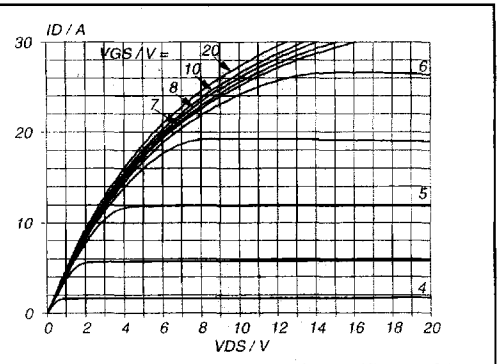


Fig.5. Typical output characteristics, T_j = 25 ˚C. $I_D = f(V_{DS})$; parameter V_{GS}

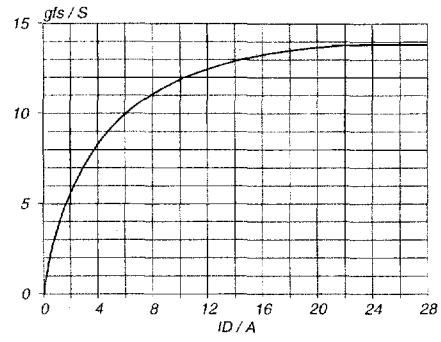


Fig.8. Typical transconductance, T_j = 25 ˚C. $g_{fs} = f(I_D)$; conditions: V_{DS} = 25 V

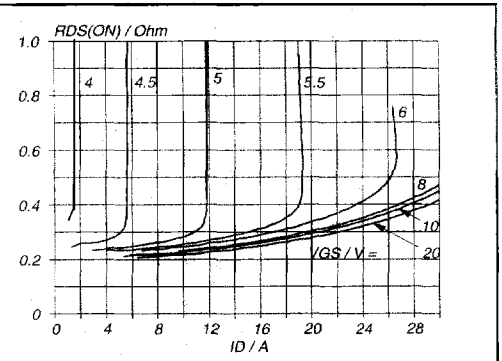


Fig.6. Typical on-state resistance, T_j = 25 ˚C. $R_{DS(ON)} = f(I_D)$; parameter V_{GS}

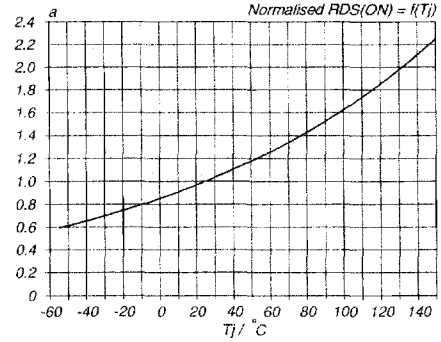


Fig.9. Normalised drain-source on-state resistance. $a = R_{DS(ON)}/R_{DS(ON)25\ ^\circ C} = f(T_j)$; I_D = 7 A; V_{GS} = 10 V

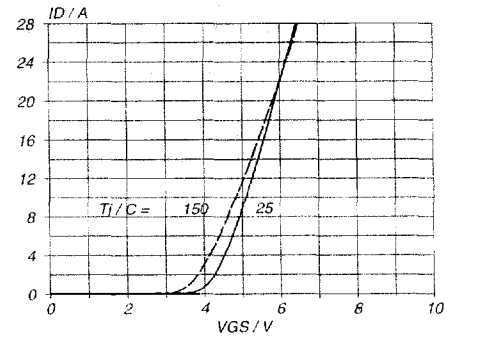


Fig.7. Typical transfer characteristics. $I_D = f(V_{GS})$; conditions: V_{DS} = 25 V; parameter T_j

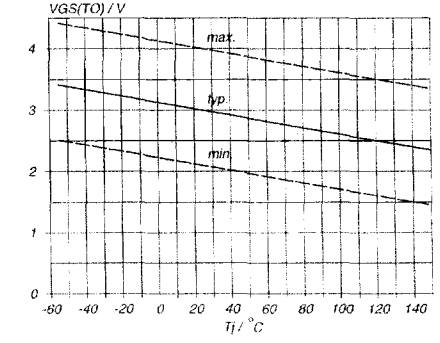


Fig.10. Gate threshold voltage. $V_{GS(TO)} = f(T_j)$; conditions: I_D = 1 mA; $V_{DS} = V_{GS}$

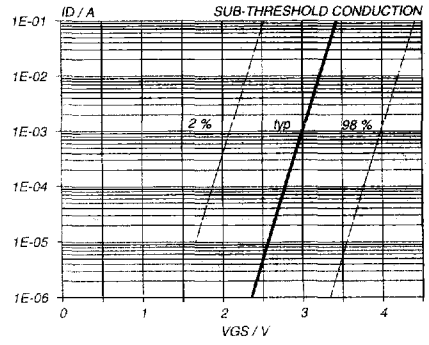


Fig.11. Sub-threshold drain current.
$I_D = f(V_{GS})$; conditions: $T_j = 25$ °C; $V_{DS} = V_{GS}$

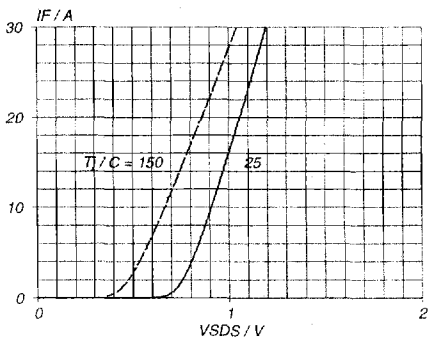


Fig.14. Typical reverse diode current.
$I_F = f(V_{SDS})$; conditions: $V_{GS} = 0$ V; parameter T_j

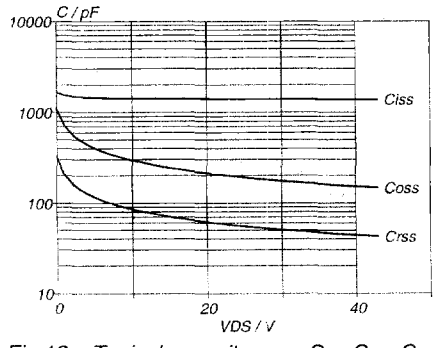


Fig.12. Typical capacitances, C_{iss}, C_{oss}, C_{rss}.
$C = f(V_{DS})$; conditions: $V_{GS} = 0$ V; $f = 1$ MHz

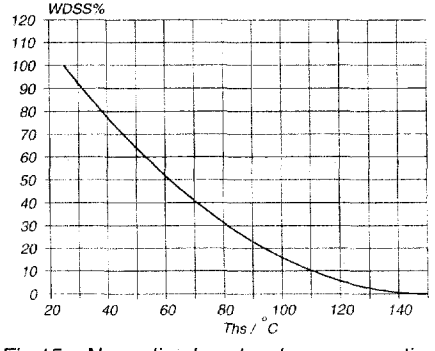


Fig.15. Normalised avalanche energy rating.
$W_{DSS}\% = f(T_{hs})$; conditions: $I_D = 14$ A

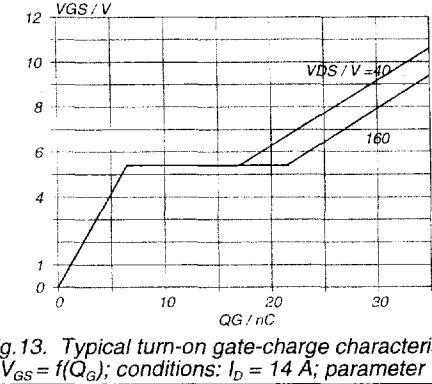


Fig.13. Typical turn-on gate-charge characteristics.
$V_{GS} = f(Q_G)$; conditions: $I_D = 14$ A; parameter V_{DS}

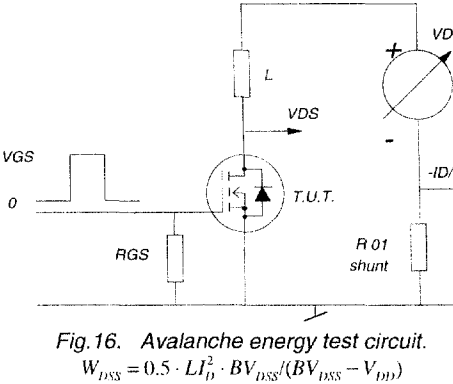


Fig.16. Avalanche energy test circuit.

$$W_{DSS} = 0.5 \cdot LI_D^2 \cdot BV_{DSS}/(BV_{DSS} - V_{DD})$$